

Application/Control No.	lo. Applicant(s)/Patent under Reexamination	
10/684,445	BAIK, KWANG JUN	
Examiner	Art Unit	
Christopher R. Lamb	2627	

Subclass	Date	Examiner
		1

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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(INCLUDING SEARC	HSIKAIEGI) 1
	DATE	EXMR
Consulted SPE Wayne Young regarding field of search	6/19/2006	CRL
EAST Search	6/21/2006	CRL
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